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- Meets or Exceeds the Requirements of ANSI Standard EIA/TIA-232-E and ITU Recommendation V.28
- Input Resistance . . . 3 kΩ to 7 kΩ Over Full EIA/TIA-232-E Voltage Range
- Input Threshold Adjustable to Meet Fail-Safe Requirements Without Using External Components
- Built-In Hysteresis for Increased Noise
 Immunity
- Inverting Output Compatible With TTL
- Output With Active Pullup for Symmetrical Switching Speeds
- Standard Supply Voltages . . . 5 V or 12 V

description

The SN75154 is a monolithic low-power Schottky line receiver designed to satisfy the requirements of the standard interface between data terminal equipment and data communication equipment as defined by ANSI Standard EIA/TIA-232-E. Other applications are for relatively short, single-line, point-to-point data transmission and for level translators. Operation is normally from a single 5-V supply; however, a built-in option allows operation from a 12-V supply without the use of additional components. The output is compatible with most TTL circuits when either supply voltage is used.

In normal operation, the threshold-control terminals are connected to the V_{CC1} terminal, even if power is being supplied via the alternate V_{CC2} terminal. This provides a wide hysteresis loop, which is the difference between the positive-going and negative-going threshold voltages. See typical characteristics. In this mode of operation, if the input voltage goes to zero, the output voltage will remain at the low or high level as determined by the previous input.

For fail-safe operation, the threshold-control terminals are open. This reduces the hysteresis loop by causing the negative-going threshold voltage to be above zero. The positive-going threshold voltage remains above zero as it is unaffected by the disposition of the threshold terminals. In the fail-safe mode, if the input voltage goes to zero or an open-circuit condition, the output will go to the high level regardless of the previous input condition.

The SN75154 is characterized for operation from 0°C to 70°C.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



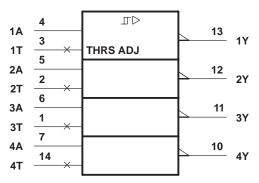
D OR N PACKAGE (TOP VIEW)					
3T [2T [1T [• 1 2 3	16 15 14] V _{CC2}] V _{CC1}] 4T		
1A 🖡	4	13] 1Y		
2A [5	12] 2Y		
3A [6	11] 3Y		
4A [7	10] 4Y		
2A [3A [4A [GND [8	9] R1†		

[†] For function of R1, see schematic

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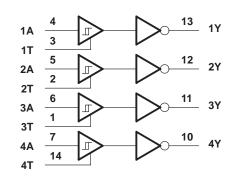
logic symbol[†]

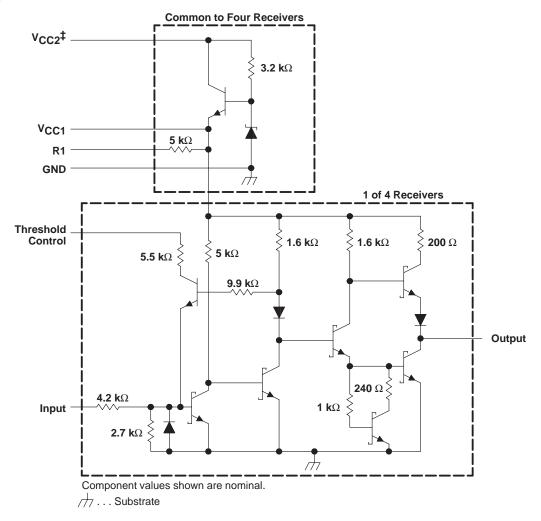


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

schematic

logic diagram (positive logic)





[‡] When V_{CC1} is used, V_{CC2} may be left open or shorted to V_{CC1}. When V_{CC2} is used, V_{CC1} must be left open or connected to the threshold control pins.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Normal supply voltage, V _{CC1} (see Note 1)	
Alternate supply voltage, V _{CC2}	14 V
Input voltage, V _I	±25 V
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range, T _{stg}	–65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: Voltage values are with respect to network GND terminal.

PACKAGE	T _A ≤ 25°C POWER RATING	DERATING FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING				
D	950 mW	7.6 mW/°C	608 mW				
N	1150 mW	9.2 mW/°C	736 mW				
NS	625 mW	5.0 mW/°C	400 mW				

DISSIPATION RATING TABLE

recommended operating conditions

	MIN	NOM	MAX	UNIT
Normal supply voltage, V _{CC1}	4.5	5	5.5	V
Alternate supply voltage, V _{CC2}	10.8	12	13.2	V
High-level input voltage, VIH (see Note 2)	3		15	V
Low-level input voltage, VIL (see Note 2)	-15		-3	V
High-level output current, I _{OH}			-400	μΑ
Low-level output current, IOL			16	mA
Operating free-air temperature, T _A	0		70	°C

NOTE 2: The algebraic convention, where the less positive (more negative) limit is designated as minimum, is used in this data sheet for logic and threshold levels only, e.g., when 0 V is the maximum, the minimum limit is a more negative voltage.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST FIGURE	TEST COND	DITIONS	MIN	түр†	МАХ	UNIT	
\/	Positive-going input	Normal operation	1			0.8	2.2	3	V	
VIT+	threshold voltage	Fail-safe operation				0.8	2.2	3	v	
\/. _	Negative-going input	Normal operation	1			-3	-1.1	0	V	
VIT-	threshold voltage	Fail-safe operation				0.8	1.4	3	V	
\ <i>\</i> .	Hysteresis voltage	Normal operation	1			0.8	3.3	6	V	
V _{hys}	$(V_{IT+} - V_{IT-})$	Fail-safe operation				0	0.8	2.2	v	
VOH	High-level output voltage		1	I _{OH} = -400 μA		2.4	3.5		V	
VOL	Low-level output voltage		1	I _{OL} = 16 mA			0.29	0.4	V	
				$\Delta V_I = -25 \text{ V to } -1$	4 V	3	5	7		
			2	$\Delta V_{I} = -14 \text{ V to } -3$	S V	3	5	7		
ri	Input resistance			$\Delta V_{I} = -3 \text{ V to } 3 \text{ V}$		3	6	8	kΩ	
				$\Delta V_{I} = 3 V$ to 14 V		3	5	7	1122	
				ΔV_{I} = 14 V to 25 V	/	3	5	7		
V _{I(open)}	Open-circuit input voltage		3	$I_I = 0$		0	0.2	2	V	
los	Short-circuit output current‡		4	V _{CC1} = 5.5 V,	$V_{I} = -5 V$	-10	-20	-40	mA	
ICC1	i de la companya de l		5	V _{CC1} = 5.5 V,	T _A = 25°C		20	35	mA	
ICC2	Supply current from V _{CC2}	ent from V _{CC2}		V _{CC2} = 13.2 V,	T _A = 25°C		23	40	mA	

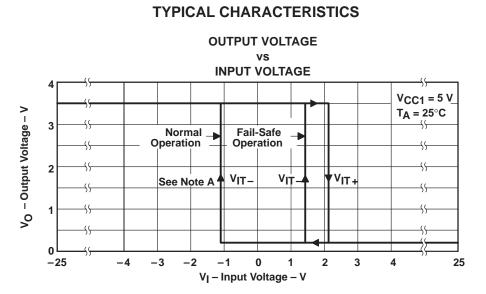
[†] All typical values are at $V_{CC1} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$. [‡] Not more than one output should be shorted at a time.

switching characteristics, V_{CC1} = 5 V, T_A = 25°C, N = 10

	PARAMETER	TEST FIGURE	TEST CO	NDITIONS	MIN	TYP	МАХ	UNIT
^t PLH	Propagation delay time, low- to high-level output					11		ns
^t PHL	Propagation delay time, high- to low-level output	6	C _L = 50 pF,	$R_L = 390 \ \Omega$		8		ns
t _{TLH}	Transition time, low- to high-level output	0				7		ns
^t THL	Transition time, high- to low-level output					2.2		ns



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NOTE A: For normal operation, the threshold controls are connected to V_{CC1}. For fail-safe operation, the threshold controls are open.

Figure 1



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PARAMETER MEASUREMENT INFORMATION

dc test circuits[†]

TEST TABLE							
TEST	MEASURE	А	Т	Y	V _{CC1}	V _{CC2}	
Open circuit input (feil acto)	VOH	Open	Open	ЮН	4.5 V	Open	
Open-circuit input (fail safe)	VOH	Open	Open	ЮН	Open	10.8 V	
	VOH	0.8 V	Open	ЮН	5.5 V	Open	
V _{IT +} min, V _{IT –} min (fail safe)	VOH	0.8 V	Open	ЮН	Open	13.2 V	
	VOH	Note A	VCC1	ЮН	5.5 V and T	Open	
V _{IT +} min (normal)	VOH	Note A	VCC1	ЮН	Т	13.2 V	
	VOH	-3 V	V _{CC1}	ЮН	5.5 V and T	Open	
V _{IL} max, V _{IT +} min (normal)	VOH	-3 V	V _{CC1}	ЮН	Т	13.2 V	
	VOL	3 V	Open	IOL	4.5 V	Open	
VIH min, VIT+ max, VIT_ max (fail safe)	VOL	3 V	Open	IOL	Open	10.8 V	
	VOL	3 V	VCC1	IOL	4.5 V and T	Open	
VIH min, VIT + max (normal)	VOL	3 V	VCC1	IOL	Т	10.8 V	
	VOL	Note B	VCC1	IOL	5.5 V and T	Open	
V _{IT} _max (normal)	VOL	Note B	V _{CC1}	IOL	Т	13.2 V	

NOTES: A. Momentarily apply -5 V, then 0.8 V.

B. Momentarily apply 5 V, then GND.

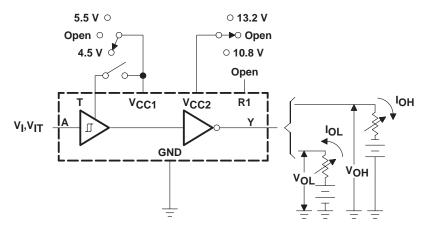


Figure 2. V_{IH} , V_{IL} , V_{IT+} , V_{IT-} , V_{OH} , V_{OL}

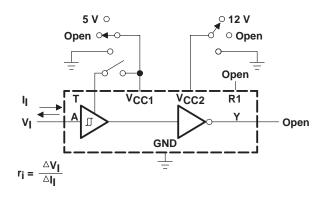
[†] Arrows indicate actual direction of current flow. Current into a terminal is a positive value.



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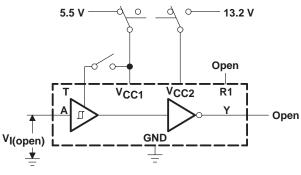
PARAMETER MEASUREMENT INFORMATION

dc test circuits[†] (continued)



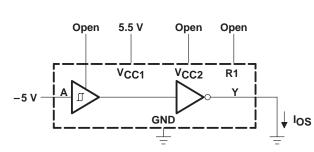
TEST TABLE						
т	V _{CC1}	V _{CC2}				
Open	5 V	Open				
Open	GND	Open				
Open	Open	Open				
VCC1	T and 5 V	Open				
GND	GND	Open				
Open	Open	12 V				
Open	Open	GND				
VCC1	Т	12 V				
VCC1	Т	GND				
VCC1	Т	Open				

Figure 3. Input Resistance



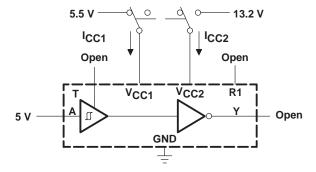
TEST TABLE						
т	V _{CC1}	V _{CC2}				
Open	5.5 V	Open				
VCC1	5.5 V	Open				
Open	Open	13.2 V				
VCC1	Т	13.2 V				





Each output is tested separately.

Figure 5. Output Short-Circuit Current



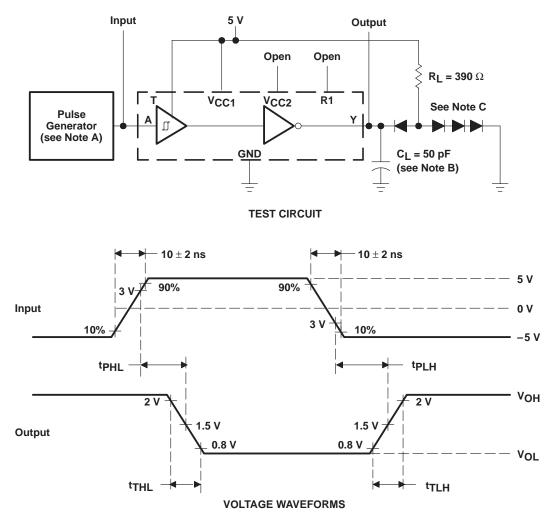
All four line receivers are tested simultaneously.

Figure 6. Supply Current

[†] Arrows indicate actual direction of current flow. Current into a terminal is a positive value.



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PARAMETER MEASUREMENT INFORMATION

- NOTES: A. The pulse generator has the following characteristics: $Z_O = 50 \Omega$, $t_W \le 200$ ns, duty cycle $\le 20\%$.
 - B. CL includes probe and jig capacitance.
 - C. All diodes are 1N3064.

Figure 6. Test Circuit and Voltage Waveforms



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